

Search Notes

Application/Control No.

10/524,389

Examiner

Lan Nguyen

Applicant(s)/Patent under
Reexamination

BAECHLE ET AL.

Art Unit

3683

SEARCHED

Class	Subclass	Date	Examiner
303	113.1	3/8/2007	XLN
	113.2		
	113.5		
	115.4		
	116.1		
	119.1		
	119.3		
188	352		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST text included	3/8/2007	XLN